	Correl Torms
	Search Terms
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7	ALARMED
m	ALARMEDS
4	ALARMING
2	ALARMINGS
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13	ASYMMETRIC
14	ASYMMETRICS
15	BINOMIAL
16	BINOMIALS
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18	COMPARED
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1	COMPARING
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25	DISTRIBUTION
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30	UMITED
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32	LOGNORMAL
36	LOGNORMALS
37	MEAN
38	MEANS
39	MONITOR
40	MONITORED
41	MONITOREDS
42	MONITORING
43	MONITORINGS
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46	POISSONS
47	PROBABILITIES
48	PROBABILITY
49	PROBABILITYS
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25	THRESHOLD
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27	95909							
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59	24184							
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	Current XRef	Retrieval Classif	Inventor	S	ပ	۵	7	m	4	R	Image Doc. Displayed	P
			Cioffi, John M. et al.	×						)	JS 20050123028	
7			Klein, Renata							<u> </u>	JS 20050096873	
၅			Shan, Jerry Z. et al.							בו	US 20050096866	
4			Gard, Eric E. et al.							<u> </u>	US 20050073683	
<u> 1</u>			Urken, Arnold B.								US 20050067493	
9	382/224		Landwehr, Val R. et al.								US 20050025357	
	128/922; 382/131		Lang, Philipp et al.							1 2	JS 20050010106	
æ			Wegerich, Stephan W. et al.							)	US 20040260515	
<u></u>	600/509; 600/513		Geva, Amir et al.				,				JS 20040230105	
10	702/20		Ecker, David J. et al.				П			ח	US 20040209260	
11			Lambert, Diane et al.		_	•					JS 20040204906	
12			Shusterman, Vladimir								JS 20040193064	
13	607/45		Marom, Shimon et al.					-		ח	US 20040131998	
14	128/203.12		John, Erwin R. et al.			··· =				_⊃_	US 20040079372	
15			Wegerich, Stephan W. et al.							<u> </u>	US 20040078171	
16	711/114; 711/203		Fisk, David C.							2	JS 20040054850	
17			Oldale, Alison et al.							Э	US 20040054572	
18			Geile, Michael J.		:						US 20040042387	

Current XRef	Retrieval Classif	Inventor	s	U	۵	7	м	4	S	Image Doc. Displayed	ΡΤ
		Fisk, David C.							ے	JS 20040025162	
		Intriligator, Devrie S. et al.								US 20030220740	
		Bennett, Levitan S							ر	US 20030208429	
		Crowder, George E. JR.								US 20030195718	
		Ding, Yiping et al.								JS 20030167151	
		Wegerich, Stephan W. et al.						<u> </u>		US 20030139908	
		Wiederhold, Mark D. et al.								JS 20030135097	
		Mannila, Heikki et al.									
		Hougaard, Philip									
		Ueno, Reiko et al.									
		Godwin, Bryan W.						_			
		Partridge, Craig et al.					_				
		Christodoulou, Athena et al.									
	:	Ben-Gal, Irad et al.		-							
		Balson, William E. et al.									
		Geile, Michael J. et al.									

	Current XRef	Retrieval Classif	Inventor	s	U	۵.	. 7	8	4	2	Image Doc. Displayed	Ы
35	700/67; 700/73; 719/318		Lombardo, Joseph S et al.									
36			Wegerich, Stephan W. et al.									
37			Haitsma, Jaap Andre et al.									I. *
38	382/260; 382/261; 382/275; 708/300		McCarthy, Sean T. et al.									
39			Zhu, Qingsheng et al.									
40	725/129; 725/131		Dapper, Mark J. et al.									
41	370/911; 375/222; 719/328		Sarnikowski, Scott et al.									
42			Intriligator, Devrie S. et al.									
43	380/235; 455/402		Dapper, Mark J. et al.									
44	370/208		Dapper, Mark J. et al.									
45	·		DAPPER, MARK J. et al.									
46			SOLUM, JEFF et al.									
47			BREDE, JEFFREY et al.		,							
48			DAPPER, MARK J. et al.								•	

	Current XRef	Retrieval Classif	Inventor	S	၁	۵	2	8	4	2	Image Doc. Displayed	٦
49			BREDE, JEFFREY et al.								·	
20			Wegerich, Stephan W. et al.									
51	455/403		Dapper, Mark J. et al.									
52	340/934		Mintz, Josef									
23	340/934		Mintz, Josef									
54	702/20		Schwartz, David C. et al.									
22			Gray, William F. et al.									
26			Keller, Kevin A.									
57			Kenyon, Stephen C. et al.									
28	709/203		Chirashnya, Igor et al.			-						
29			Sweeney, Robert J. et al.									
9	455/452.2		Geile, Michael J. et al.									
61	700/33; 700/97; 705/7; 706/45; 706/919		PARUNAK, H. VAN DYKE et al.									
62	379/56.1		Geile, Michael J. et al.									
63	707/1		McConnell, Theodore Van Fossen et al.									
64			DAPPER, MARK J. et al.									
<b>65</b>			Sweeney, Robert J. et al.									
99	341/107; 341/51		Christodoulou; Athena et al.									

	Current XRef	Retrieval Classif	Inventor	S	U	۵	2	m	4	Ŋ	Image Doc. Displayed	Ы
29			Intriligator; Devrie S et al.									
89	703/2		Wegerich; Stephan W. et al.									
69	702/183		Crowder, Jr.; George E.									
70	700/109; 702/84		Cambon; Alexander Carswell et al.									
	341/100; 370/409; 370/478;											
	370/484; 375/346; 379/56?									,		
71	455/3.01; 455/3.01; 455/3.05:		Dapper; Mark J. et al.		•							
	725/106;									,		
	725/114;											
	725/129; 725/131											
72		,	Litt; Brian et al.									
73	370/252; 702/187; 702/188; 709/224		Ding; Yiping et al.									
74	424/9.2		Hougaard; Philip									
75	370/441; 370/485		Geile; Michael J. et al.				;					

Current XRef	Retrieval Classif	Inventor	S	U	۵	7	m	5		Image Doc. Displayed
435/91.1; 435/91.2; 536/23.1; 536/24.3; 536/24.3; 536/25.3		Schwartz; David C. et al.		-						
		Dapper; Mark J. et al.						-		
66/868		Brede; Jeffrey et al.	•						-	,
455/424; 455/450; 455/509		Pruitt; Leonard et al.							-	
375/344		Dapper; Mark J. et al.								
		Intriligator; Devrie S et al.								
370/252; 702/187; 702/188; 709/224		Ding; Yiping et al.								
340/934; 701/118		Mintz; Josef								
705/7; 706/45; 706/919		Parunak; H. Van Dyke et al.					=			
370/210; 370/484; 455/3.01		Dapper; Mark J. et al.			, ,,,					
340/934; 701/118		Mintz; Josef								
348/723; 370/389; 709/202; 710/8		Geile; Michael J.		·						

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88	235/380; 341/100; 370/342; 370/395.1; 370/401; 379/56.2; 725/105		Dapper; Mark J.							i		
89	370/342; 370/474; 379/212.01		Roberts; Harold A. et al.									
06			Geile; Michael J. et al.									
91			John; Michael Sasha									
92	235/385; 342/452; 705/28; 706/18		Werb; Jay et al.									
93	708/622		Dapper; Mark J. et al.									
94	725/106; 725/128		Roberts; Harold A. et al.									
95	702/183; 702/84; 706/24		Heger; Arlen S. et al.									
96	455/561; 725/143		Brede; Jeffrey et al.									
97			Sweeney; Robert J. et al.						··			
86	370/453; 370/474; 455/562.1		Dapper; Mark J. et al.									
66	382/260; 382/261; 382/275		McCarthy; Sean T. et al.									
100	702/181		Board; David B. et al.									

	Current XRef	Retrieval Classif	Inventor	S	U	م	7	3 4	'n	Image Doc. Displayed	PT
101	370/401		Geile; Michael J. et al.								
102	341/100; 370/280; 375/235; 375/286		Hill; Terrance J. et al.								
103	709/217		Fort; Michael J.								
104	398/116; 398/122; 398/9		Bloom; Scott H.								
105	370/342; 455/562.1; 725/114		Dapper; Mark J. et al.								
106	714/752; 714/776		Dapper; Mark J. et al.								
107	370/458; 370/474; 370/480		Geile; Michael J. et al.								
108	375/260		Dapper; Mark J. et al.								
109			Sweeney; Robert J. et al.								
110	714/44; 714/48; 714/700		Gray; William F. et al.								
111	705/7; 714/1		Weinstock; Robert M et al.								
112	435/91.1		Schwartz; David C. et al.								
113		-	John; Erwin Roy								

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114	607/48; 607/62		John; Michael Sasha									
115	382/260; 382/275		McCarthy; Sean T. et al.									
116	342/205; 342/268; 342/93		Bunch; Brian Paul									
117	600/485; 600/509; 600/544		John; Erwin Roy						:			
118	600/544; 607/45		John; Michael S.									
119	342/71; 342/72		Fukuhara; Hiroshige et al.									
120	340/501; 600/483; 600/484; 702/181		Hripcsak; George									
121	340/508; 340/517; 340/541		Rickman; Stephen A. et al.	,								
122	342/71; 342/72		Fukuhara; Hiroshige et al.									
123	348/92; 356/443; 382/254		Gray; Robert T. et al.									
124			Lilienfeld; Pedro			-						
125	351/206; 382/222; 396/18		Daugman; John G.									
126			Corwin; Thomas L. et al.									

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127	700/29; 700/32; 700/51; 702/31		Hanson; Thomas C.									
128			Demjanenko; Victor et al.									l .
129	250/307		McNeil; James A. et al.									
130	324/102; 327/58		Sax; Robert L. et al.									
131	340/680; 700/177; 73/660		Demjanenko; Victor et al.									
132	704/252; 704/253		Moshier; Stephen L.									
133	375/356		Stover; Harris A.				-					
134			Mick; Peter et al.									
135	340/501; 340/588; 340/595; 376/217; 976/DIG.139; 976/DIG.236	-	Musick; Charles R.									
136	345/618	•	Mick; Peter et al.									
137			DIRKS GERHARD						-			
138	377/15		ALTHAUS EDWARD J				-					
139	377/16		ALTHAUS EDWARD J et al.						_	_		

	Search Terms
Ţ	LAMBERT-DIANE
7	LAMBERT-DIANES
٣	LIU-CHUANHAI
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Inventor	Lambert, Diane et al.	Chambers, John M. et al.	Lambert, Diane et al.	Lambert; Diane et al.	Chambers; John M et al.	Lambert; Diane et al.	Baulier; Gerald Donald et al.	Baulier; Gerald Donald et al.	Becker; Richard Alan et al.	Becker; Richard A. et al.	Clark; Linda A. et al.	LAMBERT, DIANE et al.	BECKER, RICHARD A et al.	LAMBERT, DIANE et al.	BAULIER, GERALD DONALD et al.
Retrieval Classif									-						
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AUTOMATED AND SELECTIVE AUTHENTICATION IN TRANSACTION-BASED NETWORKS	A method of displaying multiple time series.	Method for inspecting etched workpieces.									
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16		٠	BAULIER, GERALD DONALD et al.									
17			BECKER, RICHARD ALAN et al.									
18	356/337		CLARK, LINDA ANN et al.					<u> </u>				L



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IEEE	IEEE Conference Proceeding	Select	Article Information	
IEE CNF	IEE CNF IEE Conference Proceeding		1. Statistical analysis of a change detector based on image modeling of difference picture	difference picture
IEEE STD	IEEE Standard		Park, D.; Hush, D.R.; Acoustics, Speech, and Signal Processing, 1990. ICASSP-90., 1990 International Conference on 3-6 April 1990 Page(s):2185 - 2188 vol.4	ational Conference on
			AbstractPlus   Full Text: PDF(248 KB) IEEE CNF	
			2. Reliable detection of episodes in event sequences	
		]	Gwadera, R.; Atallah, M.; Szpankowski, W.; Data Mining, 2003. ICDM 2003. Third IEEE International Conference on 19-22 Nov. 2003 Page(s):67 - 74	
			AbstractPlus   Full Text: PDF(500 KB)   IEEE CNF	

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6 March 1998 Page(s):11/1 - 11/6

Measurement of false alarm rate in a synthetic radar environment
 Stott, G.F.; Stanfield, E.V.;
 Specifying and Measuring Performance of Modern Radar Systems (Ref. No. 1998/221), IEE Colloquium

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